-30V,-45A, 9.3mΩ P-channel Power Trench MOSFET

JMTG100P03A

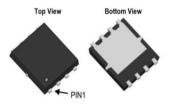
Features

- $\bullet \;\;$ Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant
- Applications
- Load Switch
- PWM Application
- Power Management

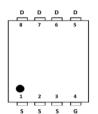
Product Summary

Parameters	Value	Unit
V_{DSS}	-30	V
$V_{GS(th)_Typ}$	-1.6	V
$I_D(@V_{GS}=-10V)$	-45	Α
$R_{DS(ON)_Typ}(@V_{GS}=-10V$	6.5	mΩ
$R_{DS(ON)_Typ}(@V_{GS}=-4.5V)$	9.3	mΩ

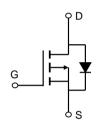




PDFN5X6-8L Top View



Pin Assignment



Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMTG100P03A	G100P03A	1	Tape&Reel	PDFN5x6-8L	5000	50000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		-30	V
V_{GS}	Gate-to-Source Voltage		±20	V
L	Continuous Drain Current	$T_C = 25^{\circ}C$	-45	А
I _D		$T_C = 100$ °C	-28	
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	А
E _{AS}	Single Pulsed Avalanche Energy		206	mJ
P_D		$T_C = 25^{\circ}C$	89	W
		$T_C = 100$ °C	36	VV
T_{J} , T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Max	Unit			
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (3)	41	°C/W			
Raic	Thermal Resistance, Junction to Case	1.4	C/VV			



Electrical Characteristics (T_J = 25°C unless otherwise specified)

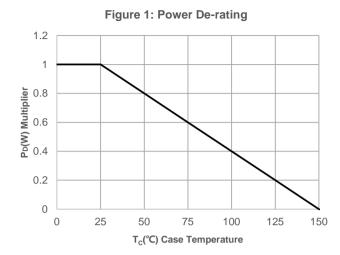
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
Off Characteristics							
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30	•	-	V	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -30V, V_{GS} = 0V$	-	-	-1.0	μА	
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA	
On Cha	On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-1.1	-1.6	-2.5	V	
R	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = -10V, I_D = -30A$	-	6.5	9.5	mΩ	
R _{DS(ON)}	Static Drain-Source ON-Resistance (*)	$V_{GS} = -4.5V, I_{D} = -20A$	-	9.3	15.6	mΩ	
Dynami	ic Characteristics						
R_{g}	Gate Resistance	f = 1MHz	-	5.6	-	Ω	
C _{iss}	Input Capacitance	V 0V V 45V	2489	3485	4705	pF	
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = -15V,$ f = 1MHz	283	397	536	pF	
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/12	240	336	454	pF	
Q _g	Total Gate Charge		44	62	83	nC	
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } -10V$ $V_{DS} = -15V, I_{D} = -20A$	7	10	13	nC	
Q_{gd}	Gate Drain("Miller") Charge	V DS = -13 V, 1D = -20A	9	12	16	nC	
Switchi	ng Characteristics						
t _{d(on)}	Turn-On DelayTime		-	16	-	ns	
t _r	Turn-On Rise Time	$V_{GS} = -10V, V_{DD} = -15V$	-	62	-	ns	
$t_{d(off)}$	Turn-Off DelayTime	$I_D = -20A$, $R_{GEN} = 3\Omega$	-	55	-	ns	
t _f	Turn-Off Fall Time		-	70	-	ns	
Body D	iode Characteristics						
Is	Maximum Continuous Body Diode Forward Current		-	-	-45	Α	
I _{SM}	Maximum Pulsed Body Diode Forward Curre	nt	-	-	-179	Α	
V _{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = -30A$	-		1.2	V	
trr	Body Diode Reverse Recovery Time	I _F = -15A, di/dt = 100A/us	15	22	29	ns	
Qrr	Body Diode Reverse Recovery Charge	1; = -10A, a/at = 100A/as	-	11.5	-	nC	

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- $2.~E_{AS}~condition:~Starting~T_J=25C,~V_{DD}=-15V,~V_G=-10V,~R_G=25ohm,~L=0.5mH,~I_{AS}=-24.08A,~V_{DD}=0V~during~time~in~avalanche.$
- 3. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.
- 4. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 0.5%.



Typical Performance Characteristics



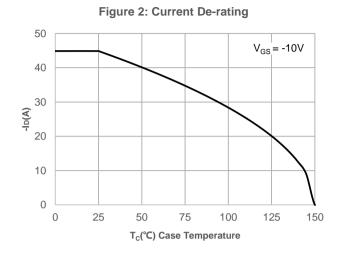
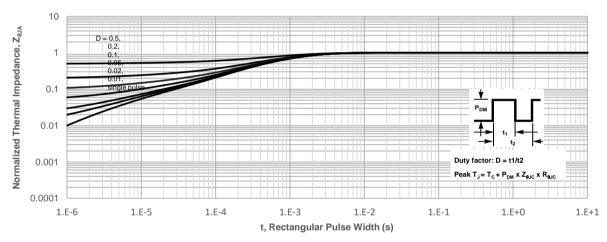
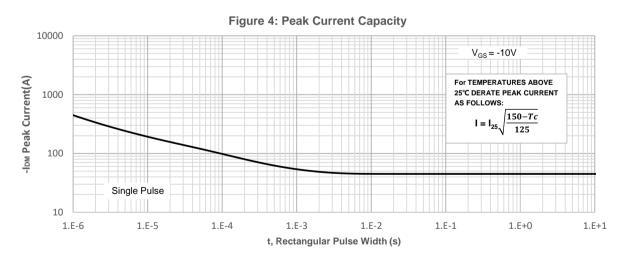


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

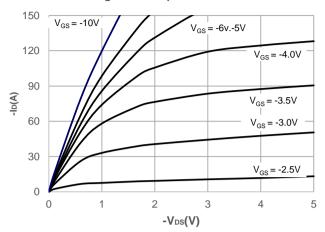


Figure 6: Typical Transfer Characteristics

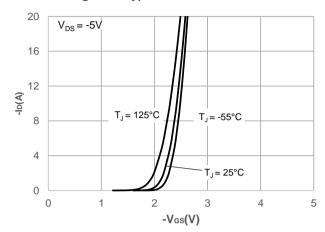


Figure 7: On-resistance vs. Drain Current

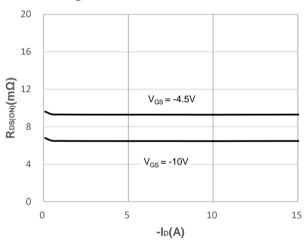


Figure 8: Body Diode Characteristics

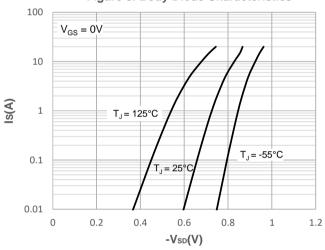


Figure 9: Gate Charge Characteristics

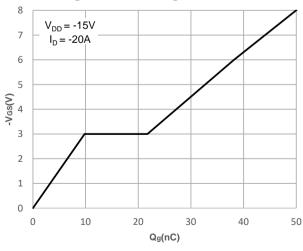
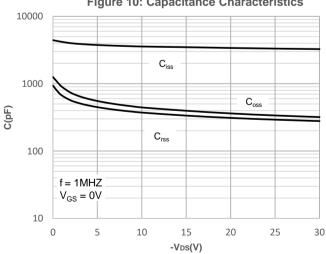


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs.
Junction Temperature

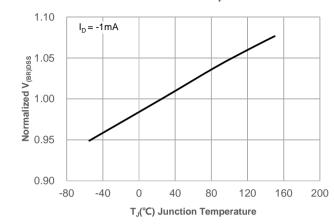


Figure 13: Normalized Threshold Voltage vs.
Junction Temperature

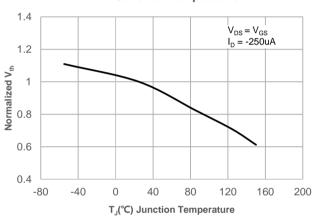


Figure 15: Maximum Safe Operating Area

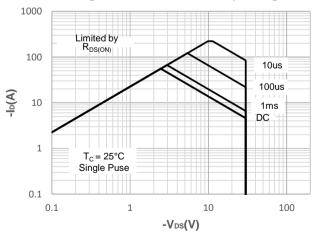
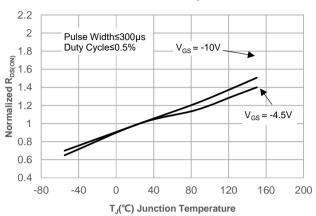
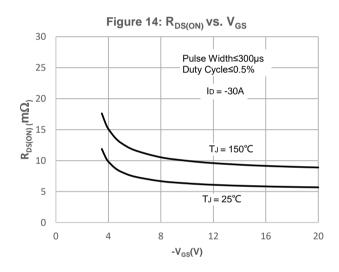


Figure 12: Normalized on Resistance vs.
Junction Temperature







Test Circuit

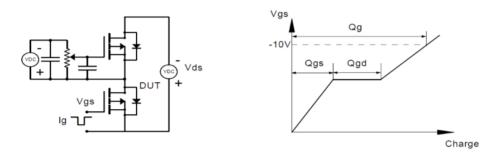


Figure 1: Gate Charge Test Circuit & Waveform

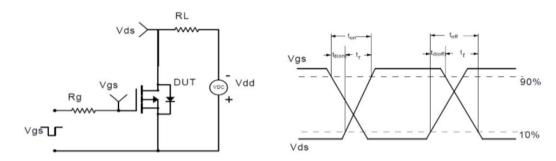


Figure 2: Resistive Switching Test Circuit & Waveform

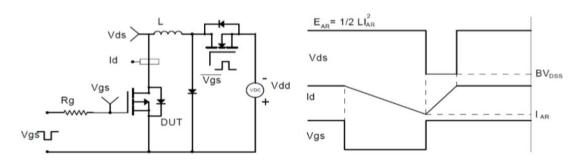


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

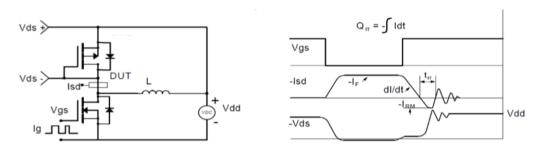
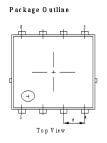


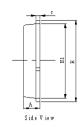
Figure 4: Diode Recovery Test Circuit & Waveform

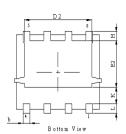
M

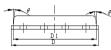


Package Mechanical Data(PDFN-5X6-8L)







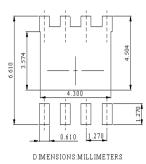


Front View

1. Dimension and tolerance per ASME Y 14.5M, 1994.
2. All dimensions in millimeter (angle in degree).

3. Dimension	s D1 and E1 do not incl	ude mold flash protrusio	ns or gate burrs.	
,	MILLIMETER			
DIM.	MIN.	NOM.	MAX.	
A	0. 9	1	1. 15	
b	0. 31	0.41	0. 51	
С	0. 24	0.32	0.4	
D	5	5. 2	5. 4	
D1	4. 95	5. 05	5. 15	
D2	4	4. 1	4. 2	
E	6. 05	6. 15	6. 25	
E1	5. 5	5. 6	5. 7	
E2	3. 42	3. 53	3. 63	
е	1. 27BSC			
Н	0.6	0. 7	0.8	
L	0.5	0. 7	0.8	
K	1.23 REF			
0			10	

Recommended Soldering Footprint



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